 earch Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/812,130	CHEN ET AL.
Examiner	Art Unit
Truc T. T. Nguyen	2833

SEARCHED			
Class	Subclass	Date	Examiner
439	877 83	11/9/2006	TN
174	261	11/9/2006	TN
29	854	11/9/2006	TN
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
see sear	ch printed	11/9/2006	TN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
see search printed	11/9/2006	TN
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